

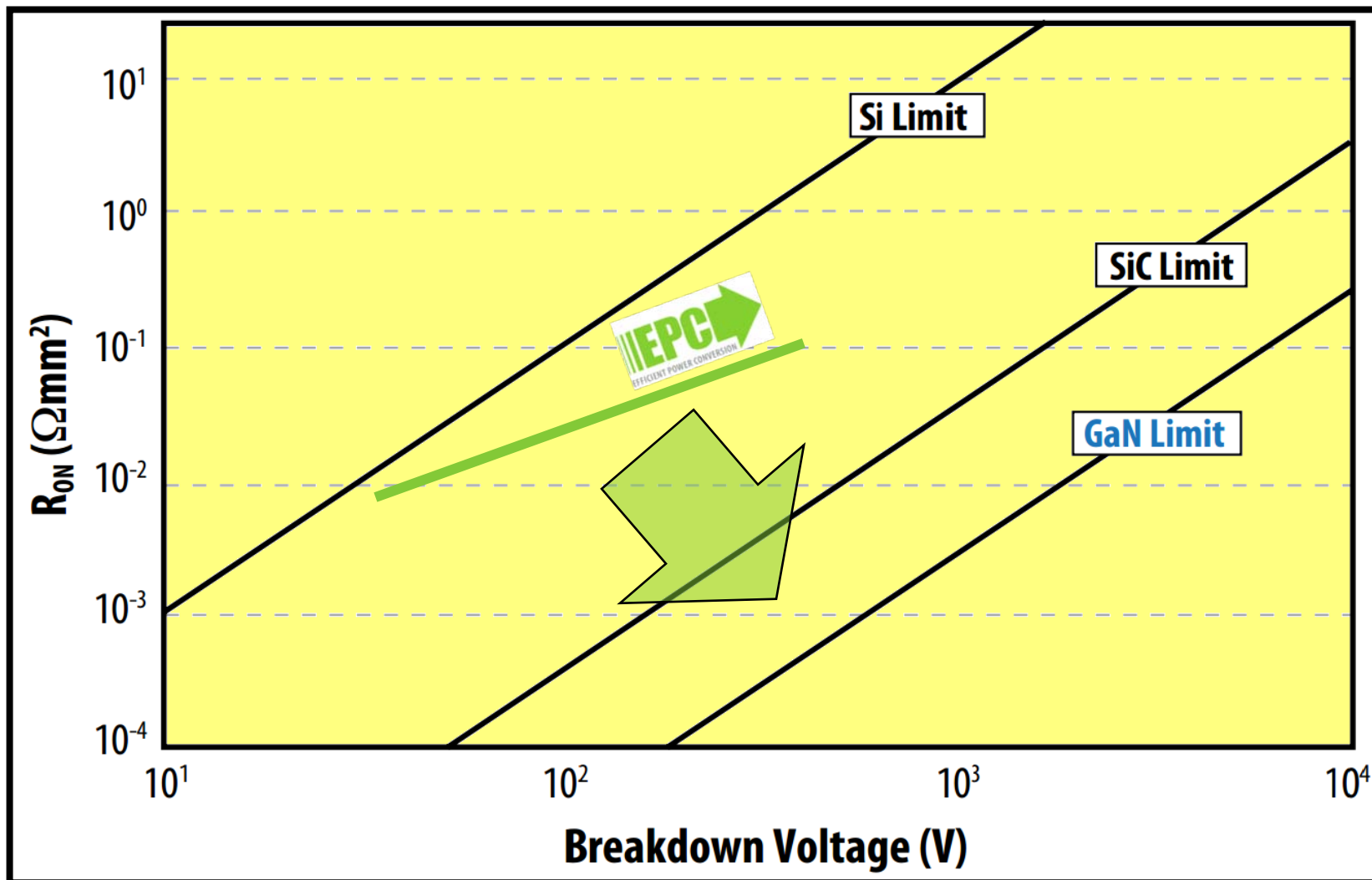
A green rectangular road sign with rounded corners is mounted on a weathered wooden post. The sign contains the text "The eGaN® FET Journey Continues" in white. The background of the entire slide is a desert landscape with a road leading towards a building at sunset. The sky is filled with white and yellow clouds, and the sun is low on the horizon, creating a bright glow. The building in the distance has a grid-like facade.

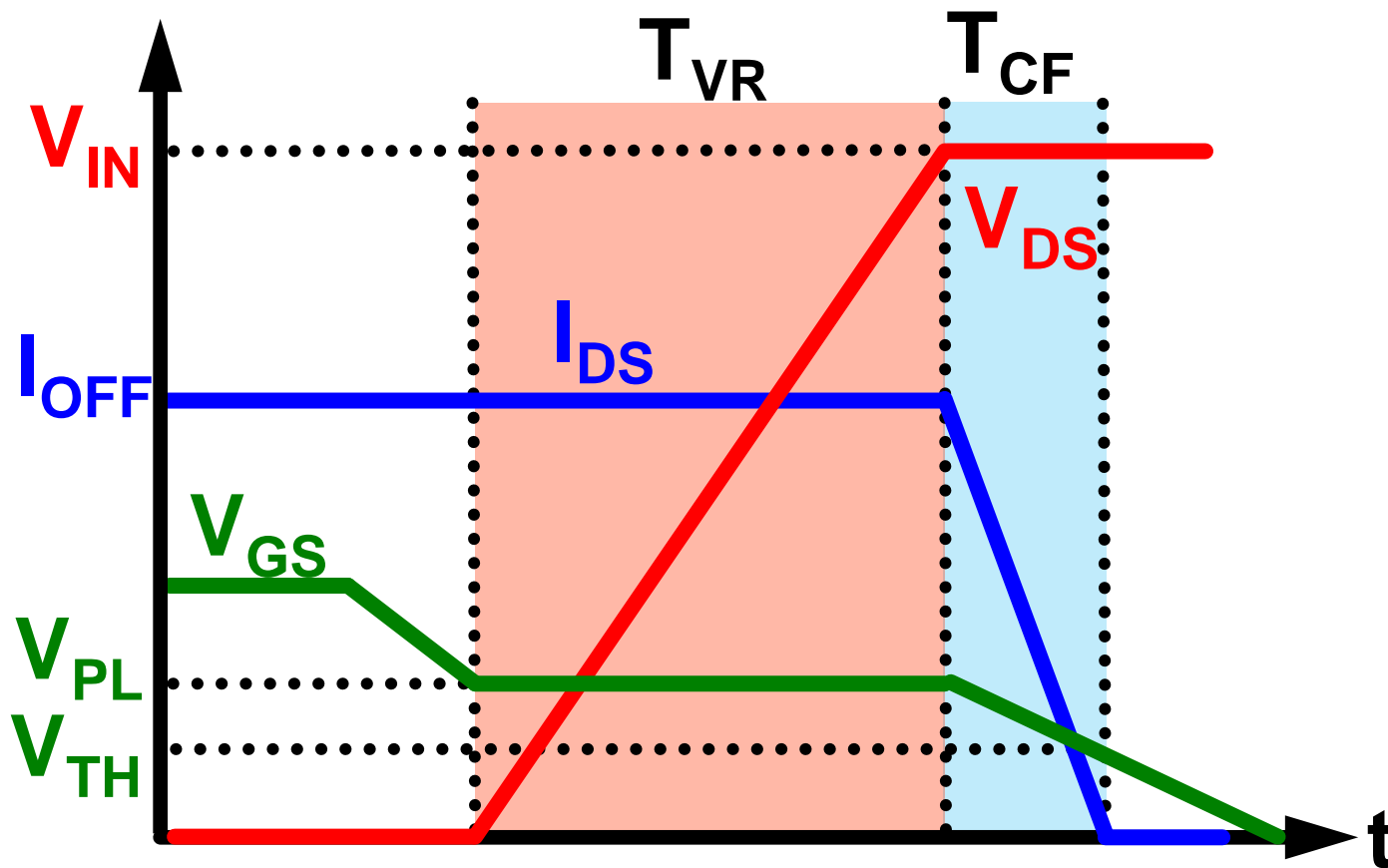
The eGaN® FET
Journey Continues

**Understanding the Effect of PCB Layout on Circuit
Performance in a High Frequency Gallium Nitride
Based Point of Load Converter**

David Reusch and Johan Strydom
Efficient Power Conversion Corporation

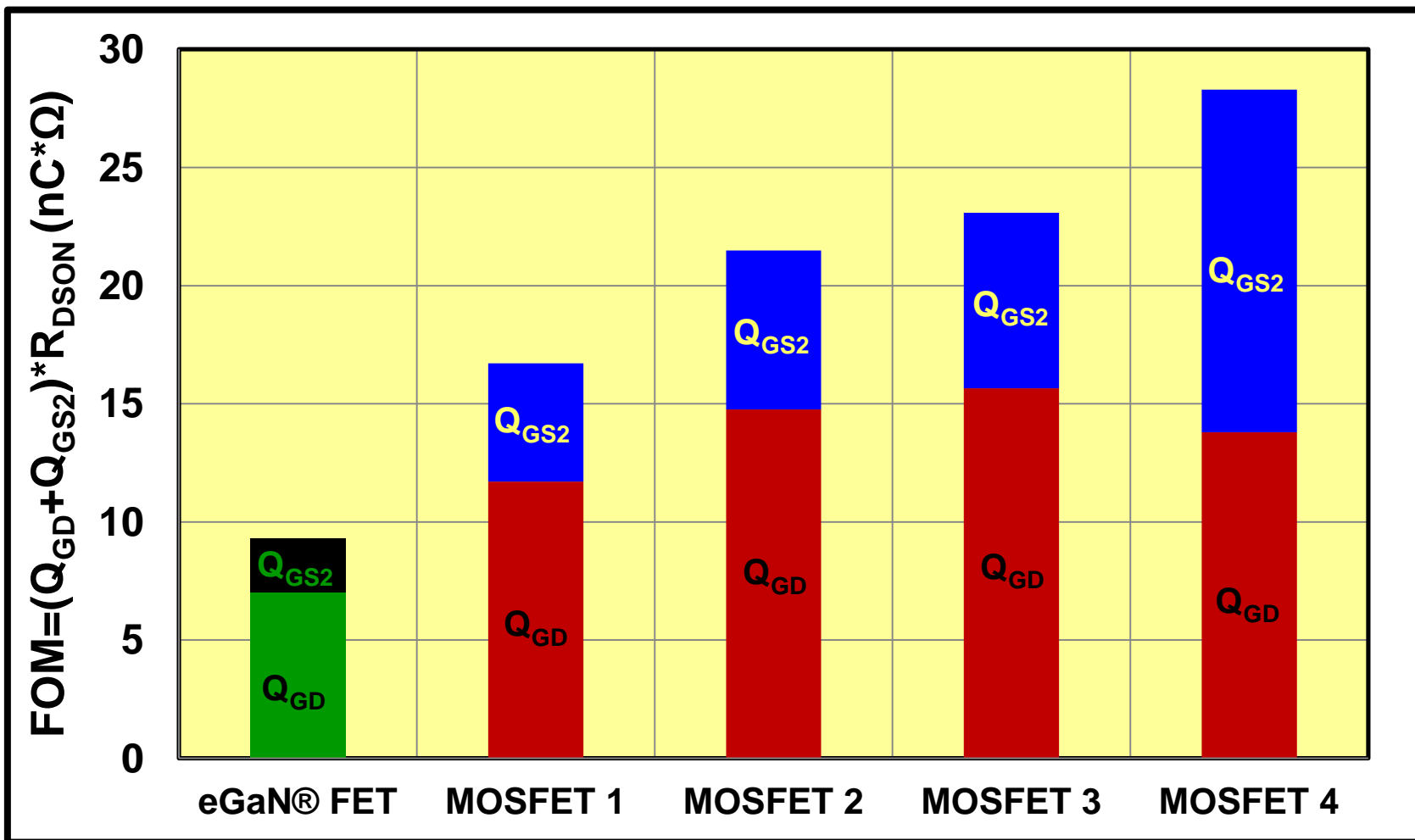
- **Overview of Current Technology**
- **Parasitic Impact on Performance**
- **Conventional Layout Comparison**
- **Optimal Layout for eGaN[®] FETs**
- **Experimental Results**
- **Summary**



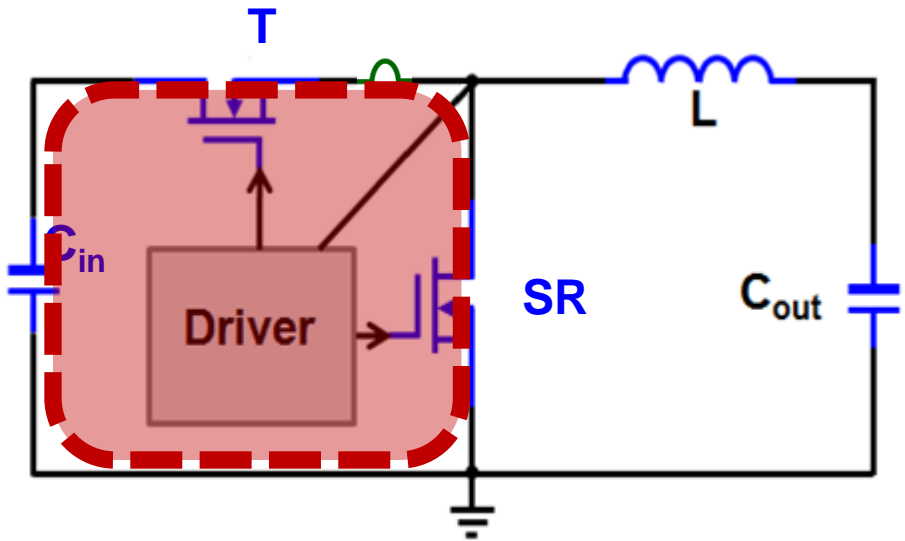


$$P_{T_{VR}} \approx \frac{V_{IN} * I_{OFF} * Q_{GD}}{2 * I_G}$$

$$P_{T_{CF}} \approx \frac{V_{IN} * I_{OFF} * Q_{GS2}}{2 * I_G}$$

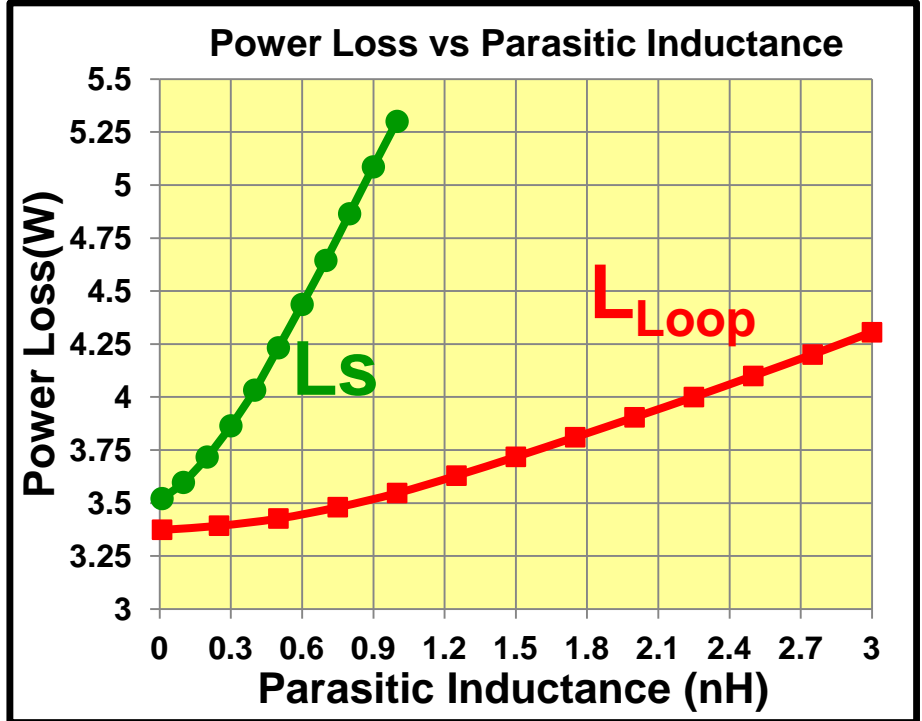


$V_{DS}=20\text{ V}, I_{DS}=20\text{ A}$

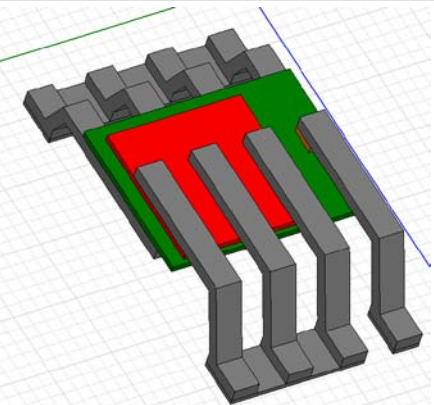


L_S : Common Source Inductance

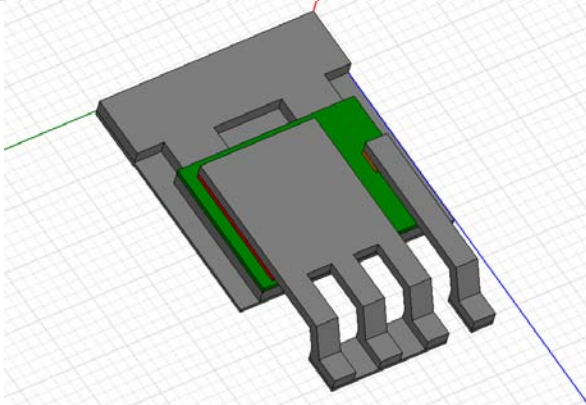
L_{Loop} : High Frequency Power Loop Inductance



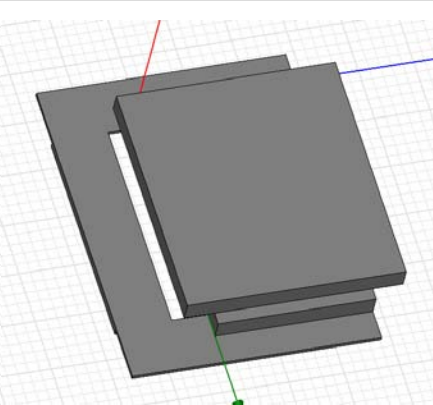
$V_{IN}=12\text{ V}$, $V_{OUT}=1.2\text{ V}$,
 $F_S=1\text{ MHz}$, $I_{OUT}=20\text{ A}$



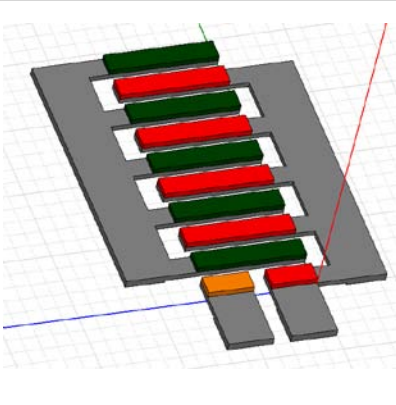
SO-8



LPAK

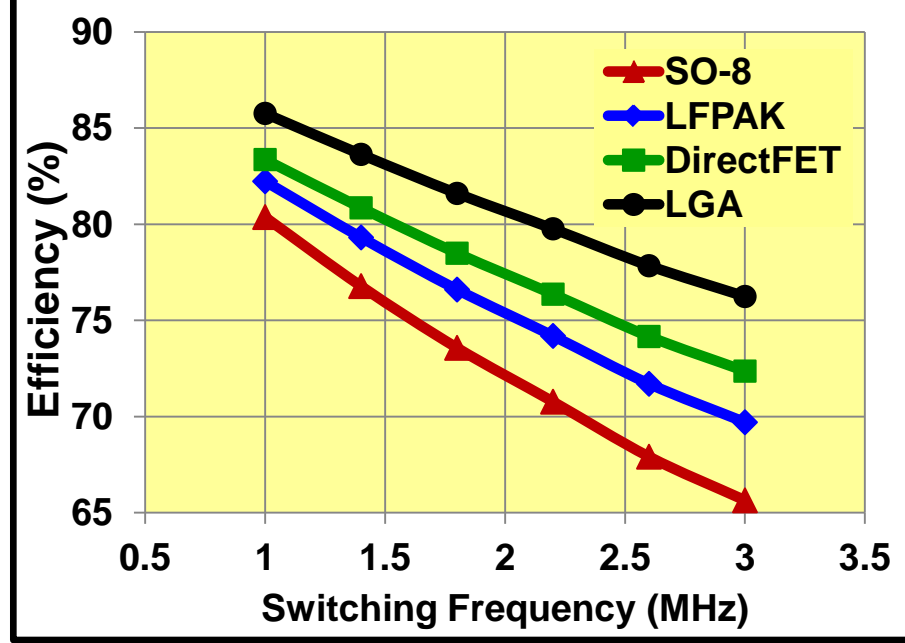
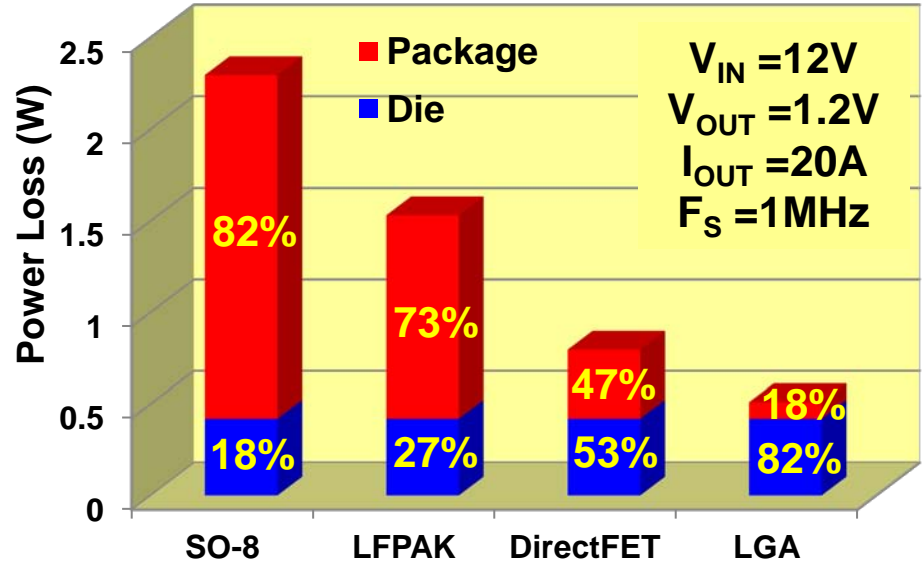


DirectFET

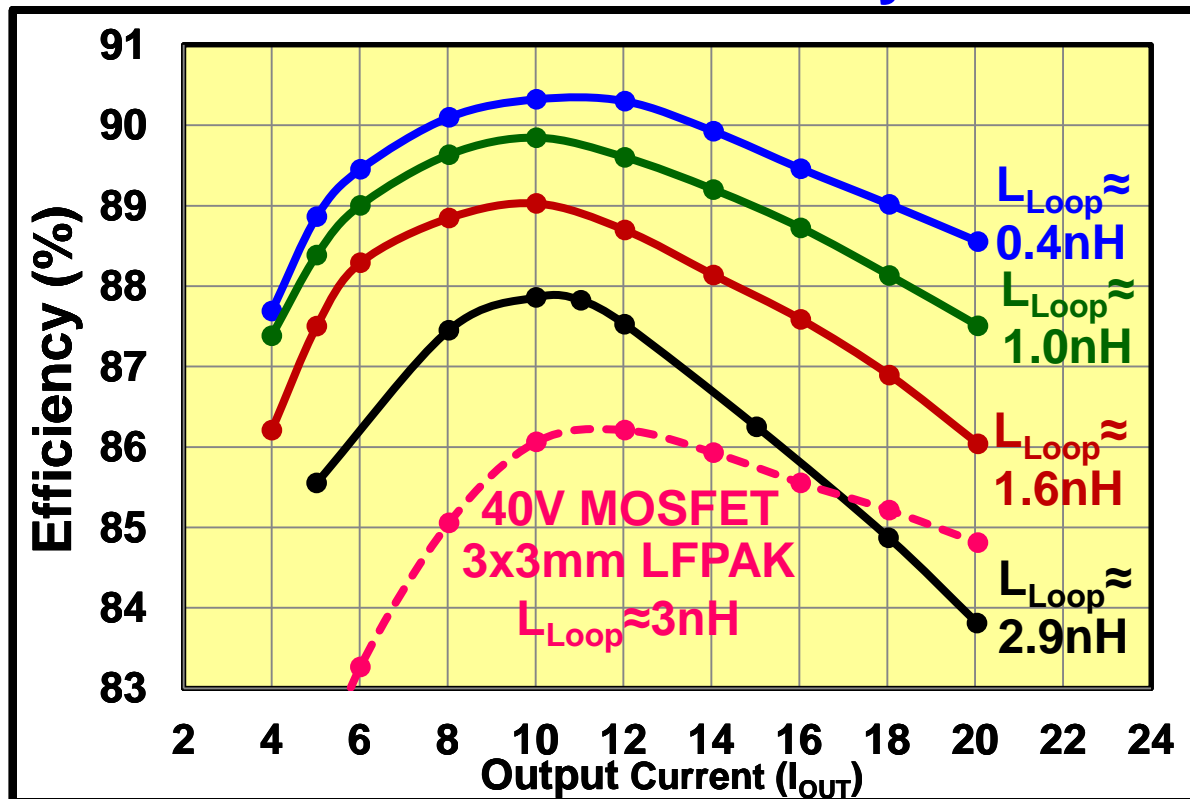


LGA eGaN

Device Loss Breakdown



Measured Efficiency

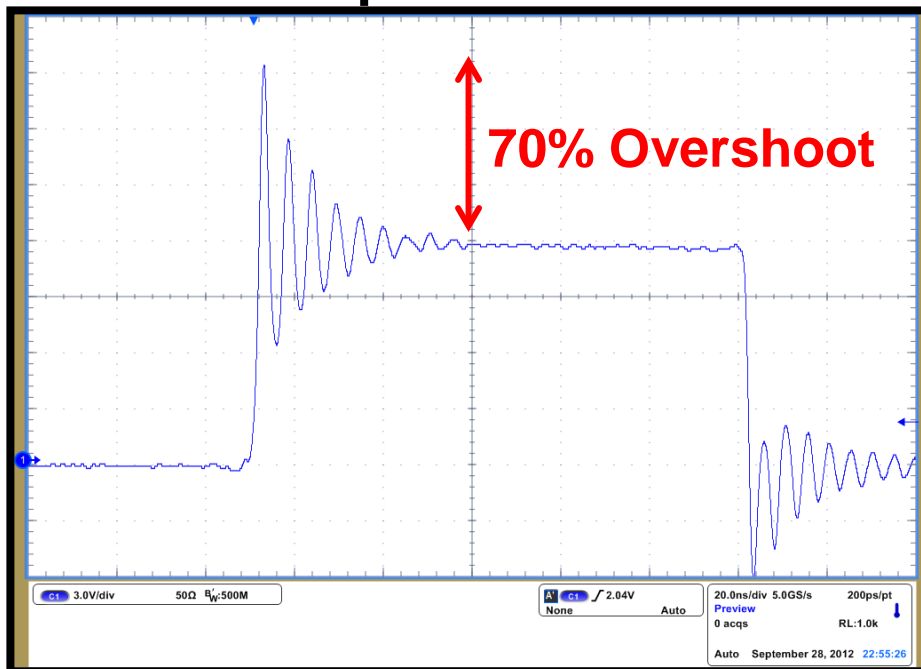


Experimental Prototype
 $L_{LOOP} \approx 0.4 \text{ nH}$

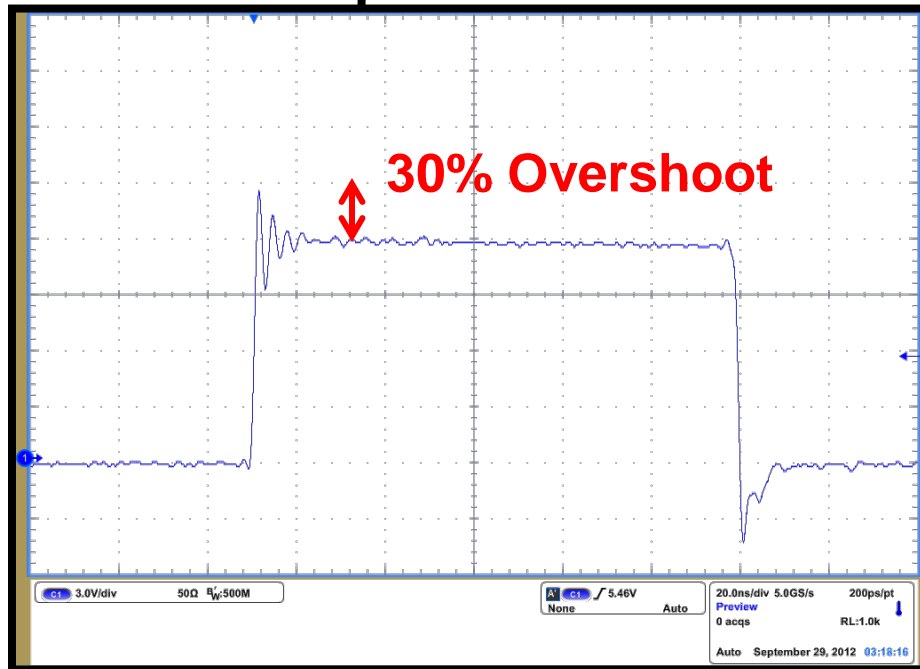


$V_{IN} = 12 \text{ V}$, $V_{OUT} = 1.2 \text{ V}$,
 $F_S = 1 \text{ MHz}$, $L = 150 \text{ nH}$

$L_{Loop} \approx 1.0 \text{ nH}$



$L_{Loop} \approx 0.4 \text{ nH}$

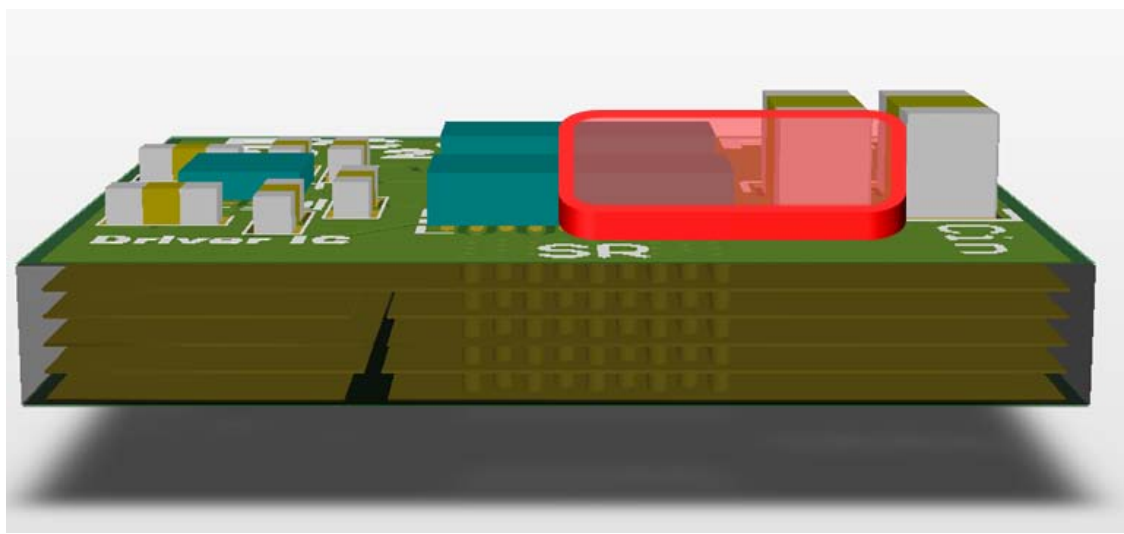
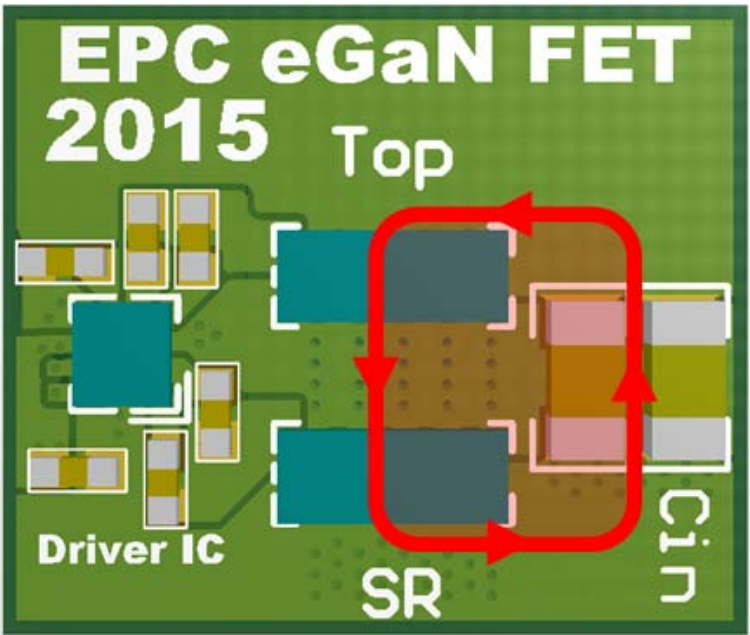


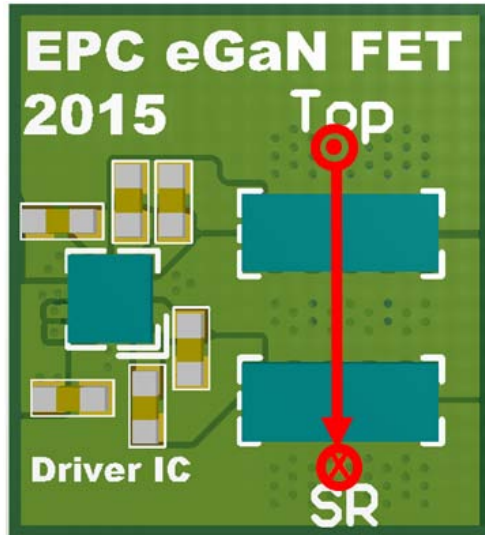
Switching Node Voltage

$V_{IN}=12 \text{ V } V_{OUT}=1.2 \text{ V } I_{OUT}=20 \text{ A}$
 $F_S=1 \text{ MHz } L=150 \text{ nH}$

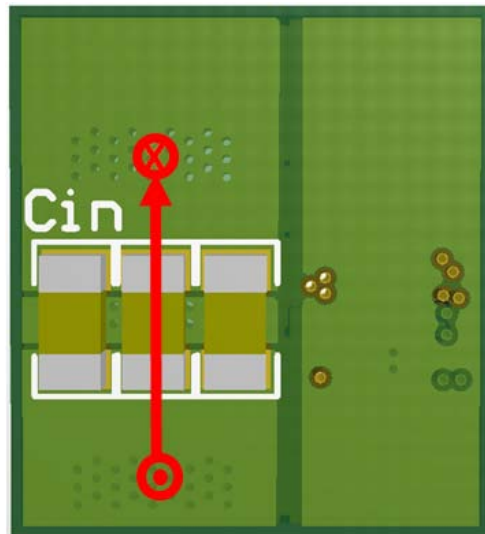
Top View

Side View



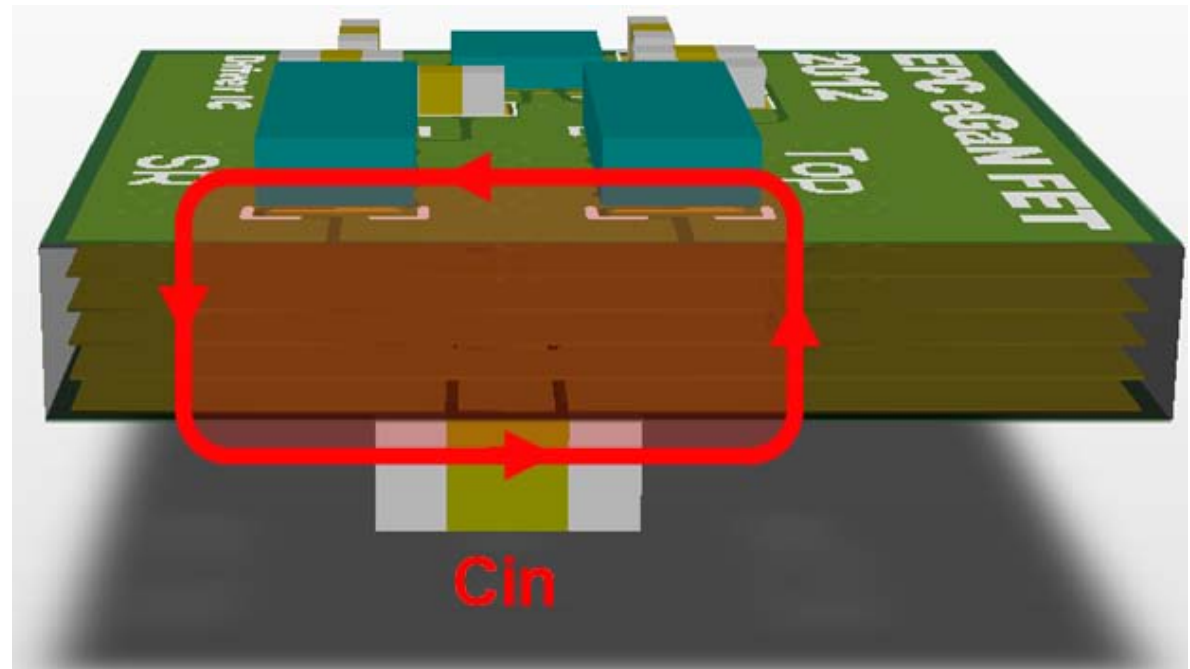


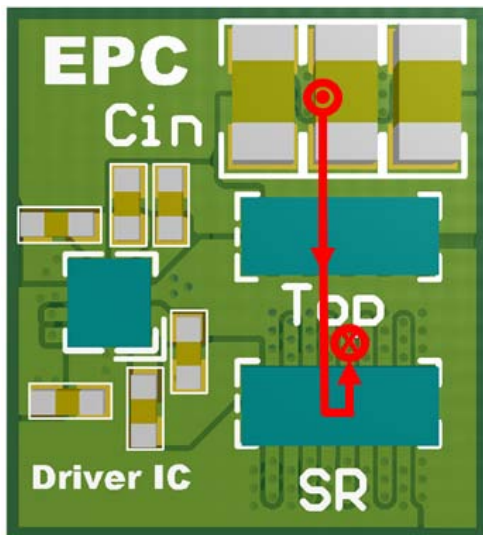
Top View



Bottom View

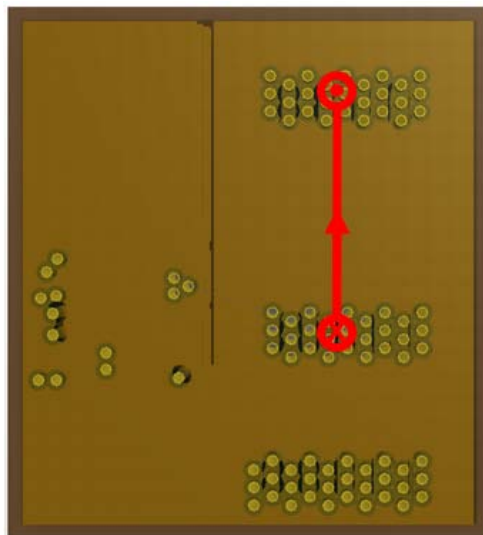
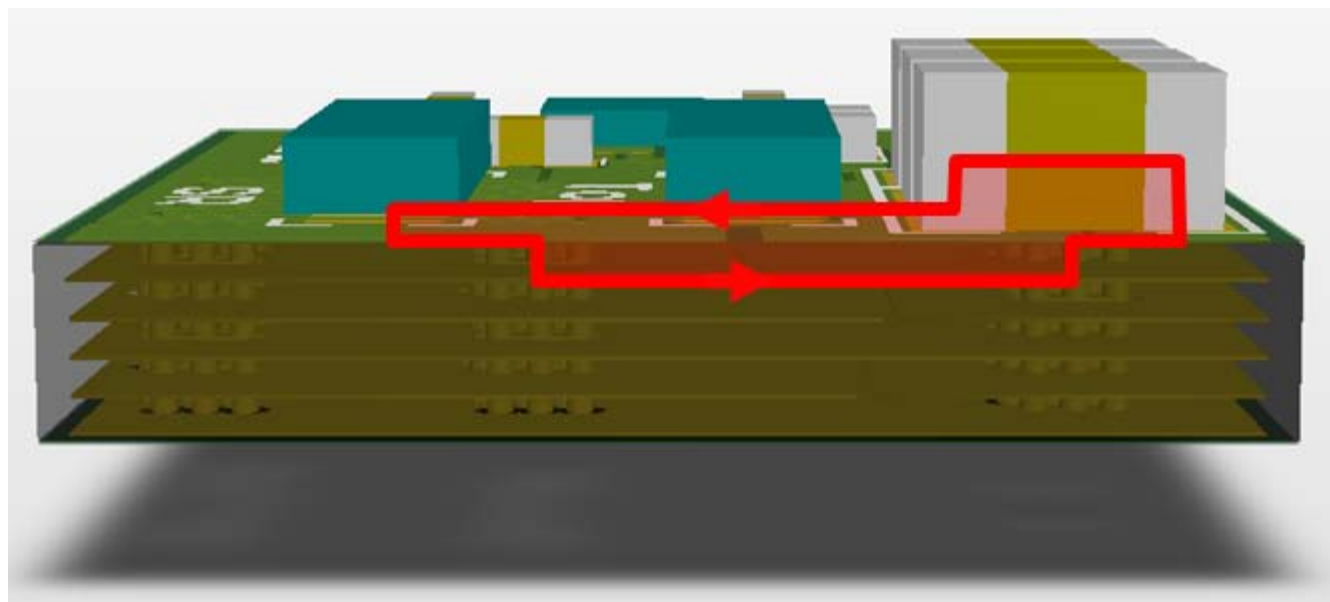
Side View





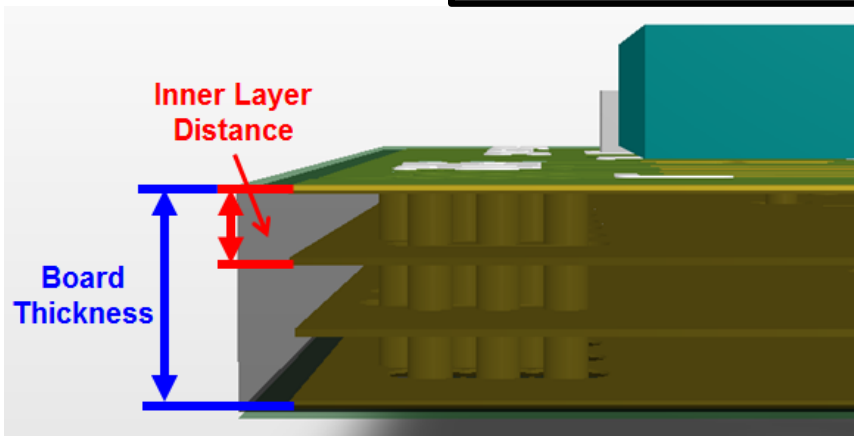
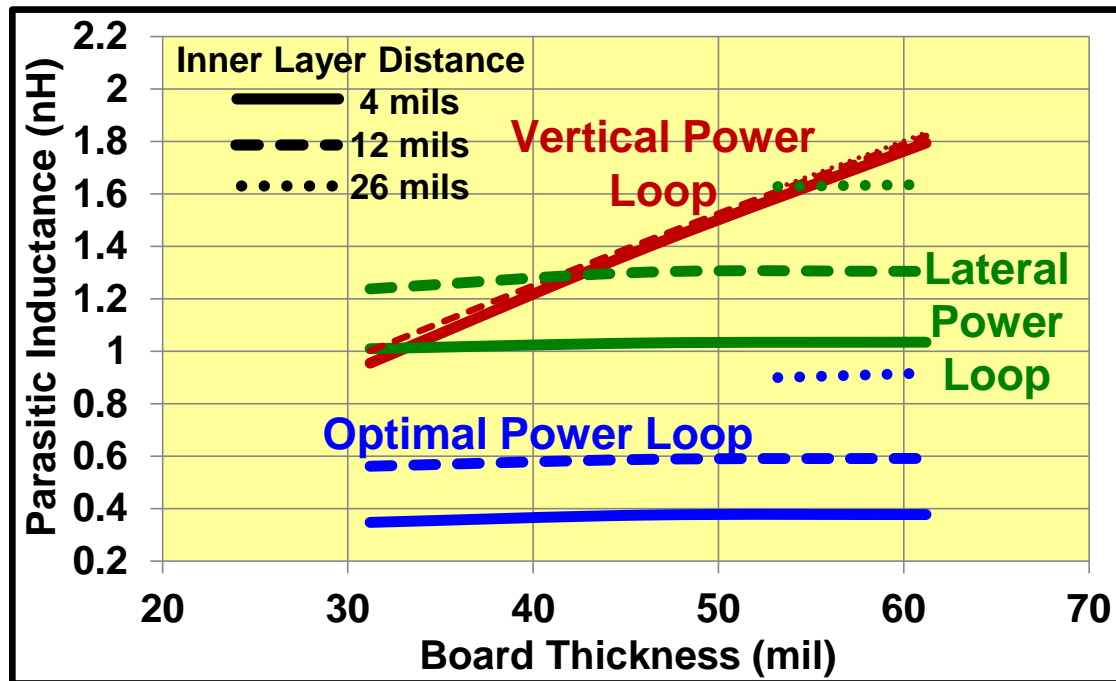
Top View

Side View



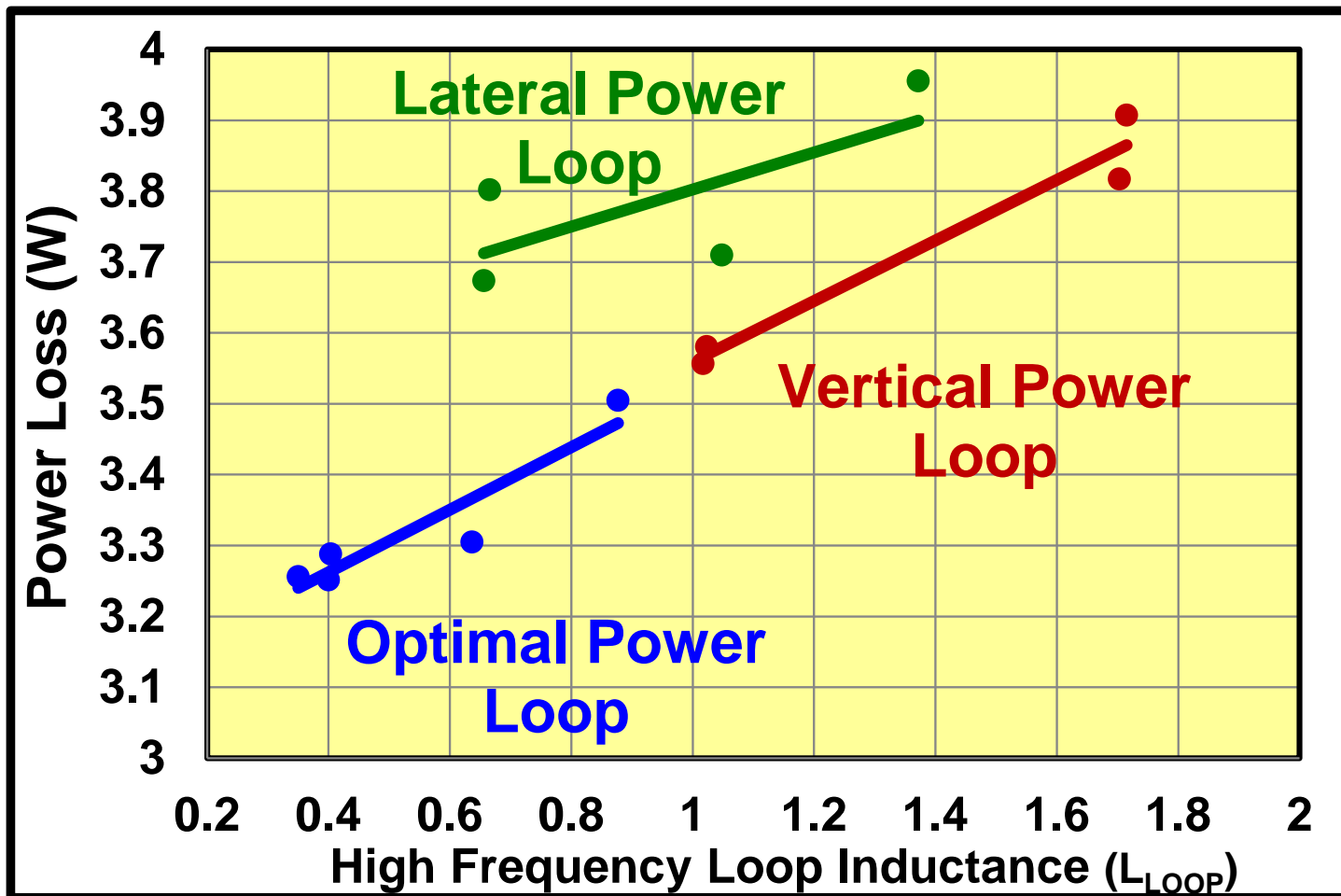
Top View
Inner Layer 1

	Lateral Loop	Vertical Loop	Optimal Loop
Single Sided PCB Capability	Yes	No	Yes
Field Self Cancellation	No	Yes	Yes
Inductance Independent of Board Thickness	Yes	No	Yes
Shield Layer Required	Yes	No	No

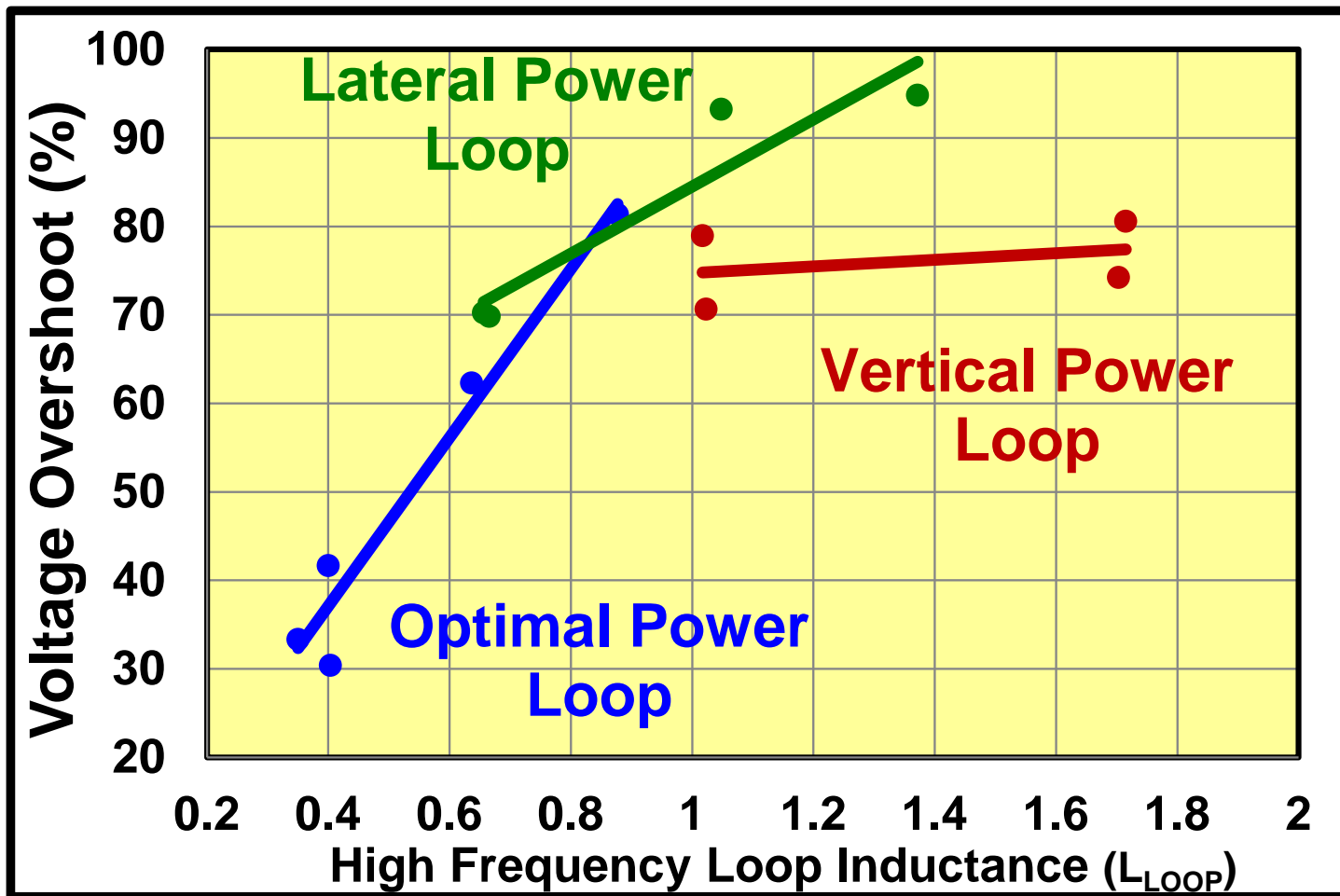


Test Cases

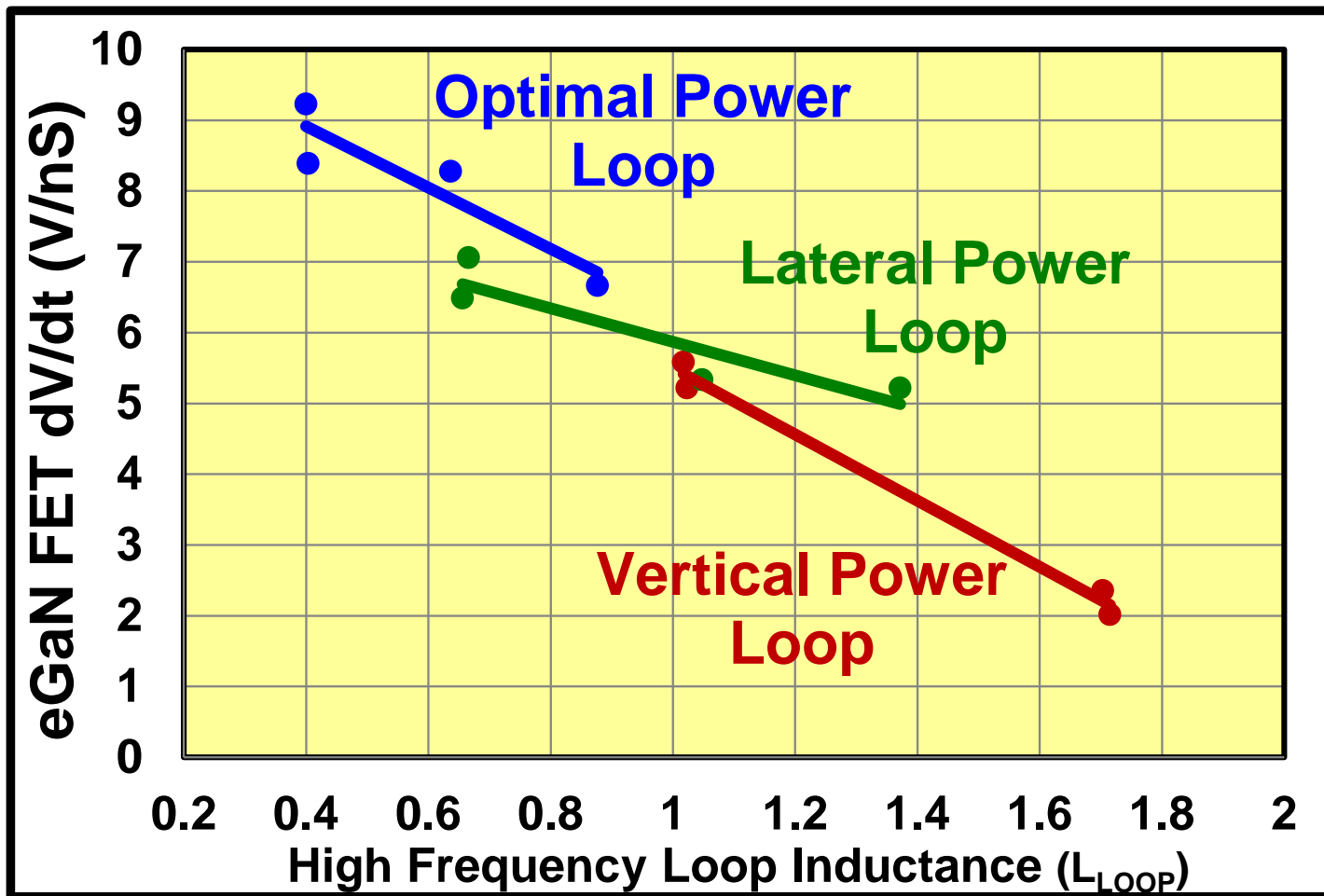
	Board Thickness (mils)	Inner Layer Distance (mils)
Design 1	31	4
Design 2	31	12
Design 3	62	4
Design 4	62	26



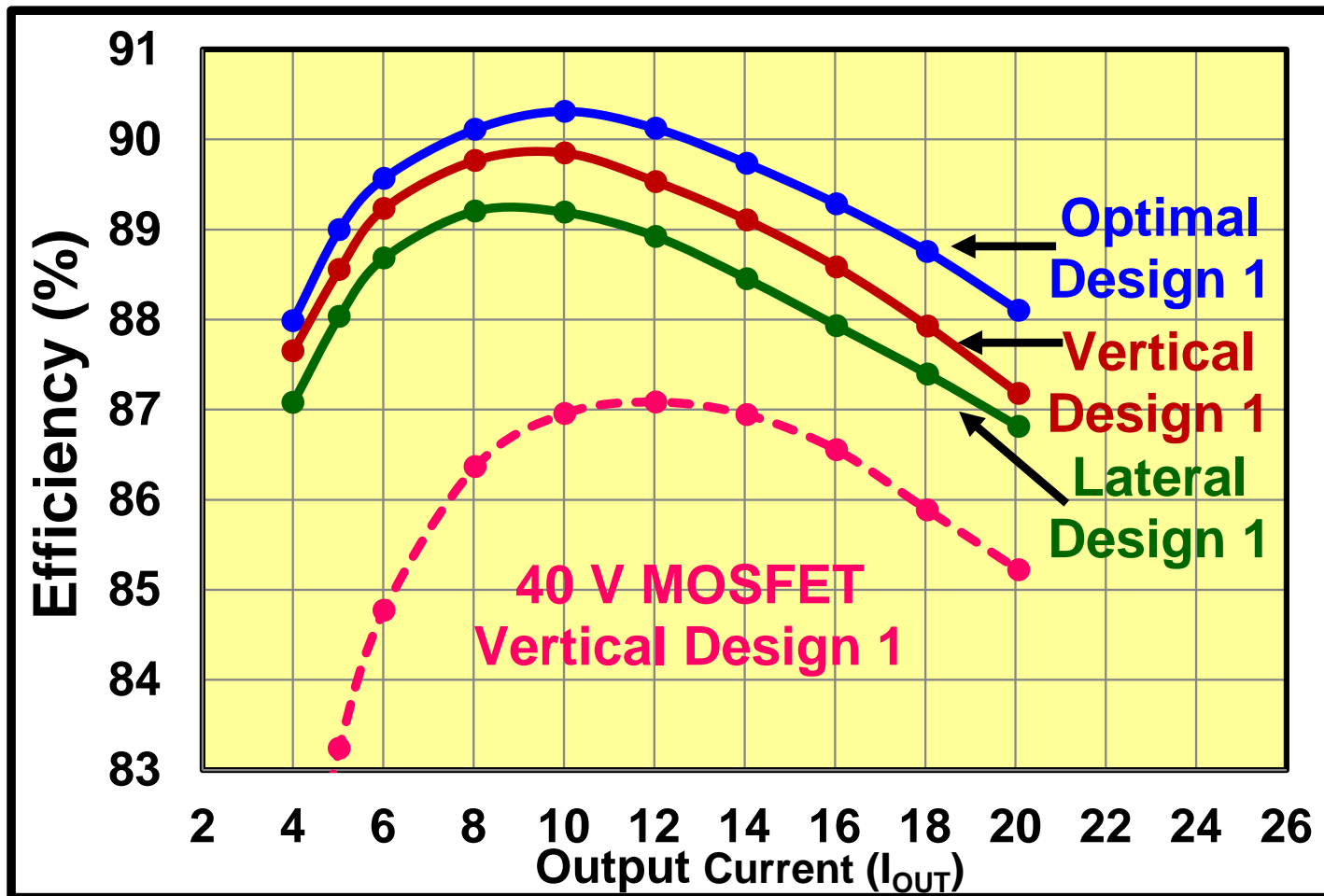
$V_{IN}=12\text{ V}$ $V_{OUT}=1.2\text{ V}$ $I_{OUT}=20\text{ A}$ $F_S=1\text{ MHz}$ $L=300\text{ nH}$
T/SR: EPC2015 Driver LM5113



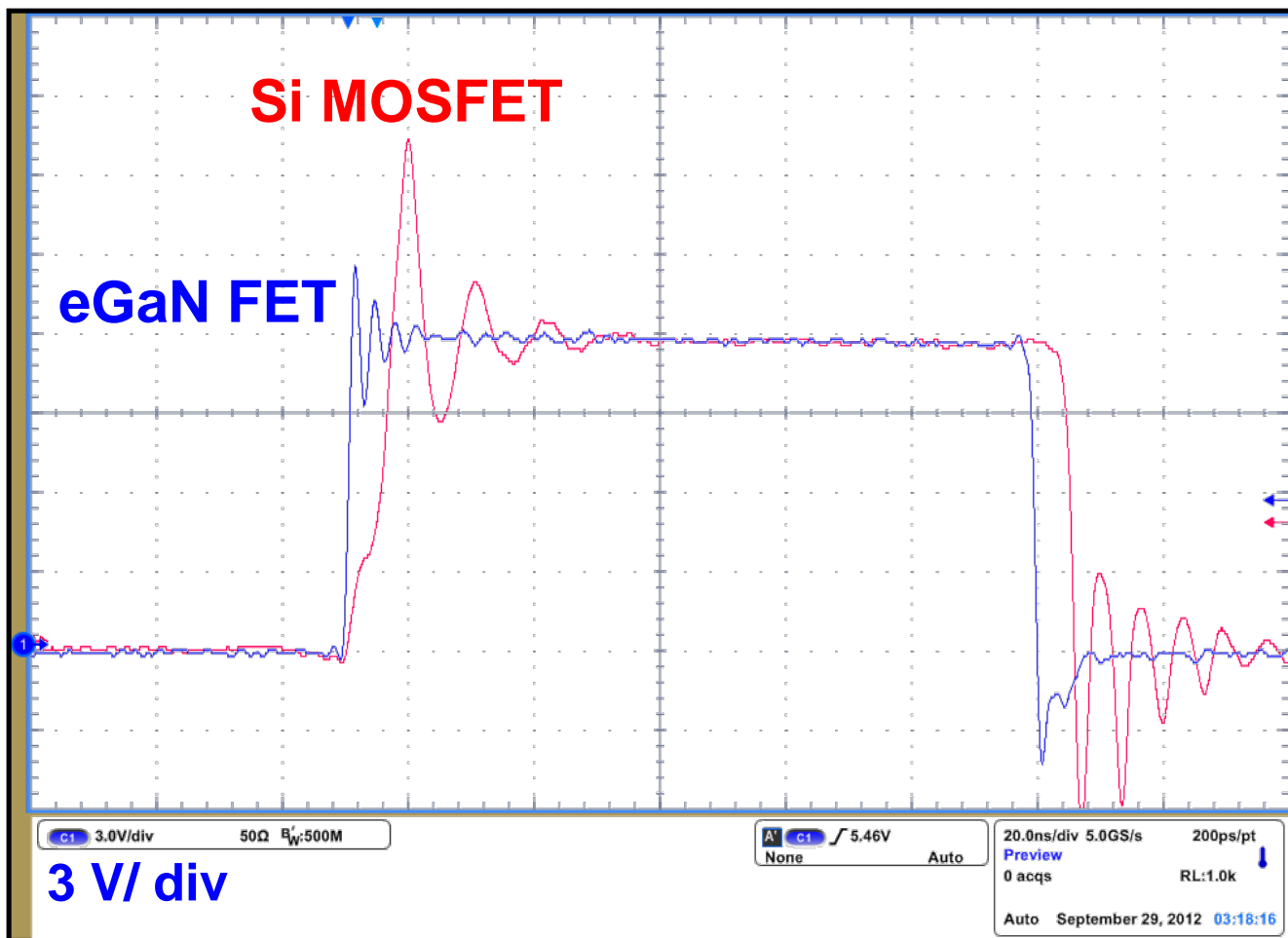
$V_{IN}=12\text{ V}$ $V_{OUT}=1.2\text{ V}$ $I_{OUT}=20\text{ A}$ $F_S=1\text{ MHz}$ $L=300\text{ nH}$
T/SR: EPC2015 Driver LM5113



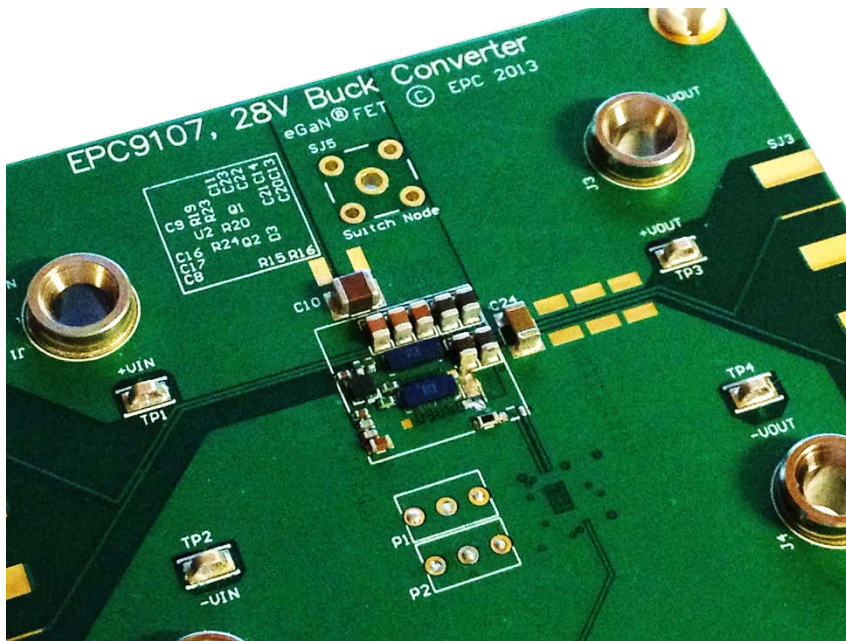
$V_{IN}=12\text{ V}$ $V_{OUT}=1.2\text{ V}$ $I_{OUT}=20\text{ A}$ $F_S=1\text{ MHz}$ $L=300\text{ nH}$
T/SR: EPC2015 Driver LM5113



$V_{IN}=12\text{ V}$ $V_{OUT}=1.2\text{ V}$ $F_s=1\text{ MHz}$ $L=300\text{ nH}$
 GaN T/SR: EPC2015 Driver LM5113



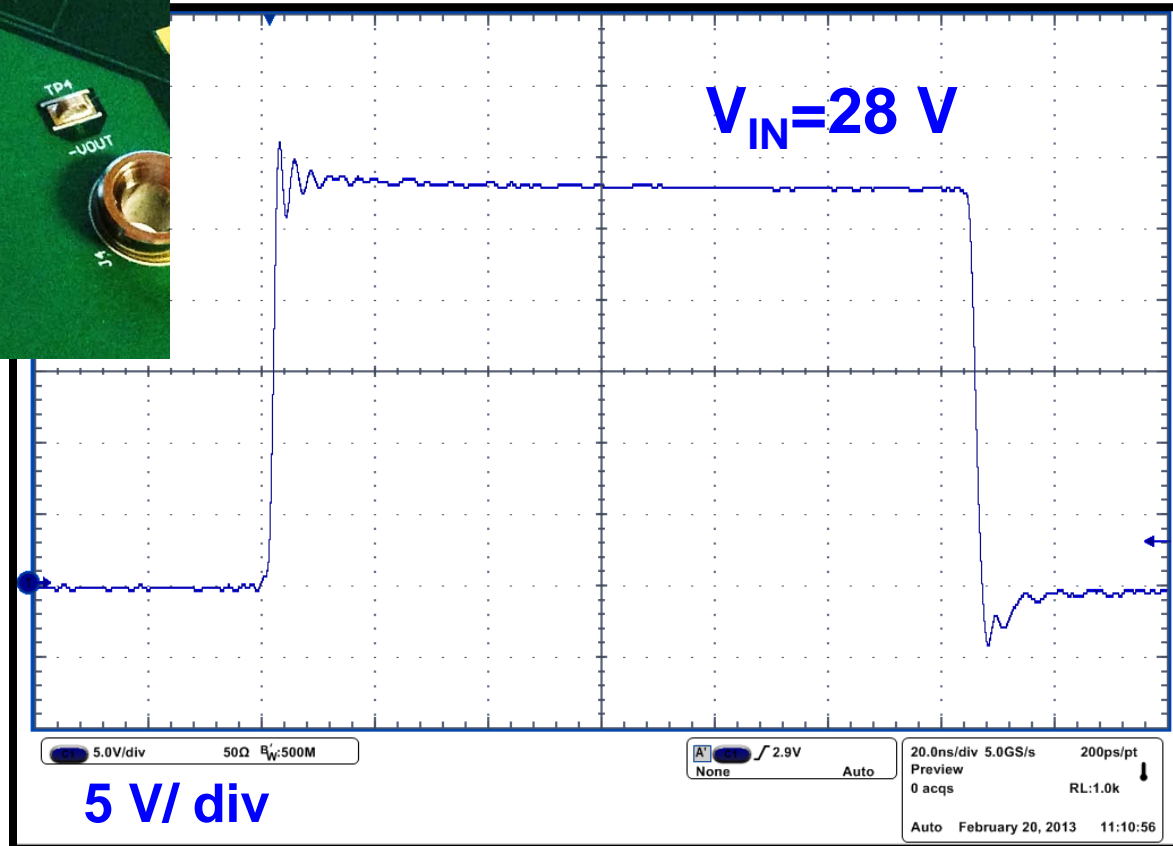
$V_{IN}=12\text{ V}$ $V_{OUT}=1.2\text{ V}$ $I_{OUT}=20\text{ A}$ $F_S=1\text{ MHz}$ $L=300\text{ nH}$ eGaN FET
T/SR: EPC2015 MOSFET T:BSZ097N04 SR:BSZ040N04



$V_{IN}=12-28\text{ V}$ $V_{OUT}=3.3\text{ V}$
 $I_{OUT}=15\text{ A}$ $F_S=1\text{ MHz}$
2 x EPC2015

Switching Node Voltage

$V_{IN}=28\text{ V}$ $I_{OUT}=15\text{ A}$



eGaN FETs improve performance in high switching frequency converters:

- Lower FOM $(Q_{GD}+Q_{GS2}) * R_{DSON}$
- Lower Package Parasitics
- PCB Layout Limits Performance
- Optimizing Layout Enhances Performance



*The end of the
road for silicon.....*

*is the beginning of
the eGaN FET
journey!*

